

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/827,248
Filing Date April 4, 2001
Inventor David R. Hembree
Assignee Micron Technology, Inc.
Group Art Unit 2829
Examiner V. Nguyen
Attorney's Docket No. MI22-1684
Title: Methods of Processing a Workpiece, Methods of Communicating Signals With
Respect to a Wafer, and Methods of Communicating Signals Within a Workpiece
Processing Apparatus

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No
admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 12/7/06

Attorney:


James D. Shaurette
Reg. No. 39,833

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Sheet 1 of 1

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1684		SERIAL NO. 09/827,248	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT David R. Hembree			
					FILING DATE April 4, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
	AA	6,325,536 B1	12/4/2001	Renken et al.				
	AB	6,190,040 B1	2/20/2001	Renken et al.				
	AC	6,411,116 B1	6/25/2002	DeHaven et al.				
	AD	4,284,872	8/18/1981	Graeme, Jerald G.				
	AE	4,366,379	10/26/1982	Graeme, Jerald G.				
	AF	6,293,698 B1	9/25/2001	Avis, Roger L.				
	AG	6,037,645	3/14/2000	Kreider, Kenneth G.				
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	AK							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL	JP406310580	11/4/1994	Japan				X
	AM	JP406310580	11/4/1994	Japan (Abstract Only)			X	
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
EXAMINER				DATE CONSIDERED				
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								

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